

Thermal performance characteristics of passively cooled 1.3µm InGaAsN/GaAs double quantum well lasers

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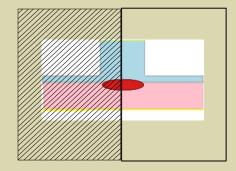
- · Generic device description
- · Description of the laser model
- · Numerical experiments
- \cdot Conclusions

Device details



Generic device structure:

QW material: InGaAsN
Number of QWs: 2
Bulk material: AlGaAs
Device length: $L = 250 \mu m$
Device width: $W = 50 \mu m$
Ridge width: $W_r = 2 \mu m$
Front facet reflectivity: $R_f = 0.3$
Back facet reflectivity: $R_b = 0.7$
Heat sink resistance: $R_{hs} = 1.0$ K/W
Front facet output power: = 10 - 15 mW
AlGaAs thermal conductiviky≑ 10 – 40 Wm ⁻¹ K ⁻¹

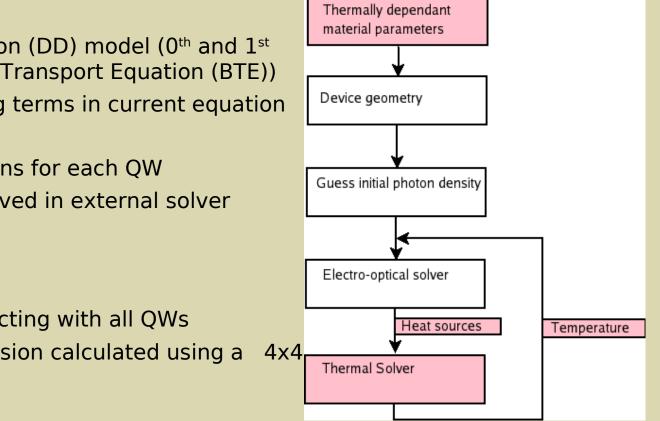


Simulation conditions:

- All simulations performed in 2D
- Half-space simulations used to reduce computation time
 - \rightarrow Possible because of device symmetry

Device simulator





Flectrical Model

- Bipolar 1D 2D Drift Diffusion (DD) model (0th and 1st ٠ moments of the Boltzmann Transport Equation (BTE))
 - Includes thermal driving terms in current equation
- Poisson's equation
- QW capture/escape equations for each QW •
- 2D lattice heat equation solved in external solver ٠

Optical Model

- Photon rate equation interacting with all QWs
- Gain and spontaneous emission calculated using a band *k.p* method

All equations solved using Newton's method

Thermal model



Thermally dependent parameters

- Electron and hole mobilities
- Band gap
- Electron affinity
- Gain (through look up table)
 - Fermi-Dirac statistics
- Spontaneous emission
- SRH recombination
- Auger recombination
- Effective densities of states
- Thermal lattice conductivity
- Maxwell-Boltzmann statistics
- Heat capacity

Heat sources

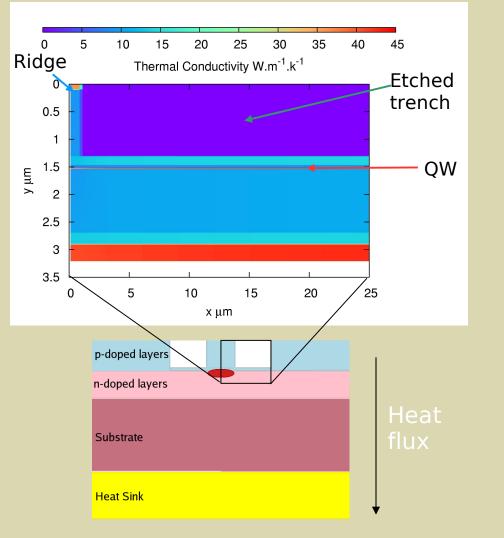
- Shockley-Read-Hall
- Auger recombination
- Free carrier absorption
- Spontaneous emission
- Joule heating
- Peltier cooling/heating

Meshing

- Separate electrical and thermal meshes
 - Mesh same over electrical region (avoids interpolation)
 - Electrical problem area small compared to thermal problem area
- Software updated to simulate p-side up/down mounting

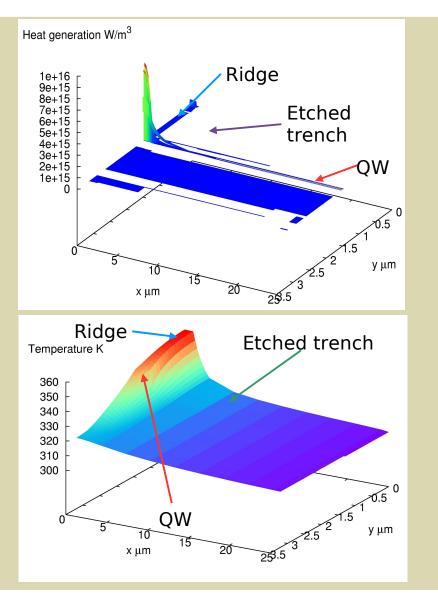
Typical thermal simulation - p-side up mounting





Can this be improved upon?

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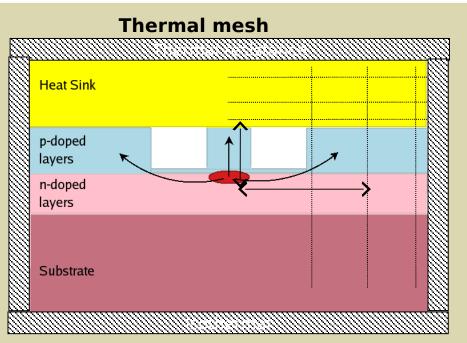
Overview of parameters investigated



- 1. Ridge width
 - How does ridge width affect the thermal performance?
- 2. Trench width
 - How does etch trench width affect thermal performance?
- 3. Trench filling
 - Can we improve device performance by filling the trenches?
- 4. Investigation of poor thermal environments
 - How do external temperature variations affect device performance?
- 5. Mounting p-side up/down
 - How does substrate thickness affect p-side up mounted devices?
- 6. Meshing
 - How far does the thermal mesh need to extend beyond the electrical mesh?

Thermal simulation window & boundary conditions



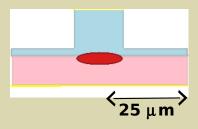


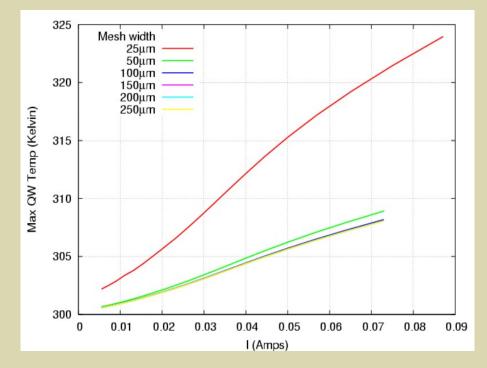
Q. How wide does the thermal mesh need to be?

- **A.** About 4 times wider than the electrical mesh Most important for p-side down mounting
- **Q.** How far does the vertical mesh need to extend into the heat sink to model thermal spreading?

A. 100µm

Electrical mesh

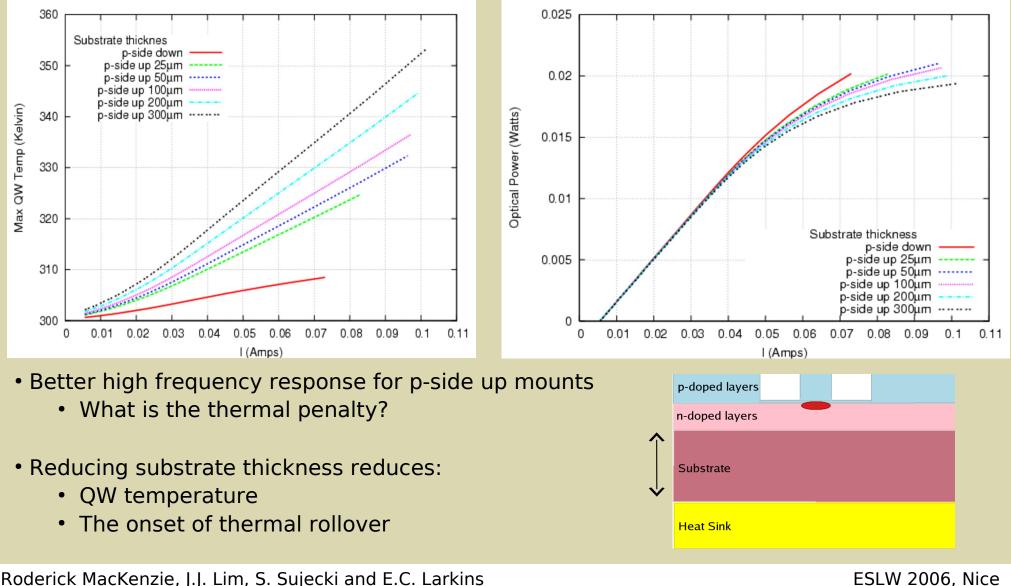




Impact of substrate height on maximum temperature 11



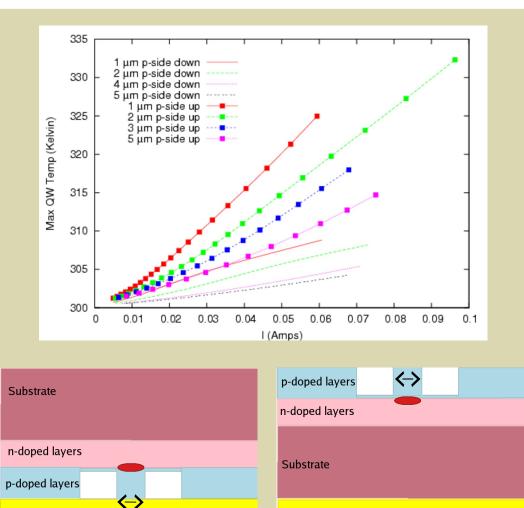




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Variation of ridge width





- How does the ridge width affect the QW temperature?
- What is the impact of p-side up mounting on this?
- Wider ridge → higher electrical conductivity → less Joule heating
- Wider ridge → bigger area → lower heat flux density → lower temperature
- P-side up mounting → no route for heat to escape up the ridge → higher QW temperature
- The ridge forms a *thermal island* that gets very hot

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Heat Sink

P-side down

Heat Sink

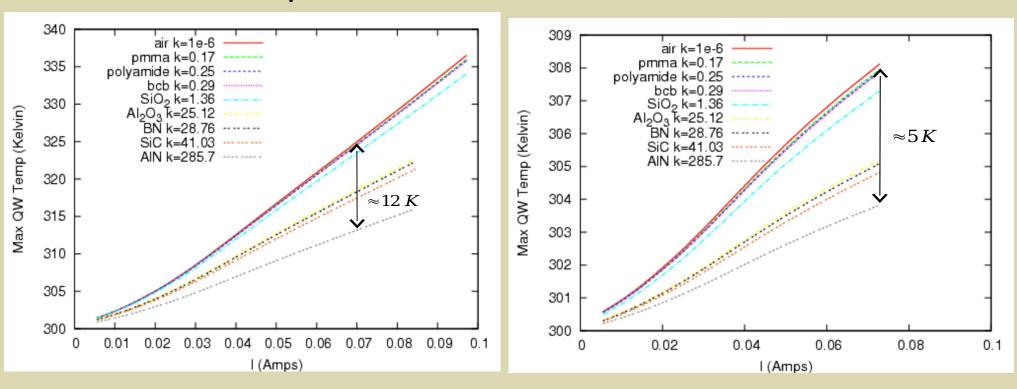
P-side up

Thermal conductivity of the etched trench



P-side up

P-side down

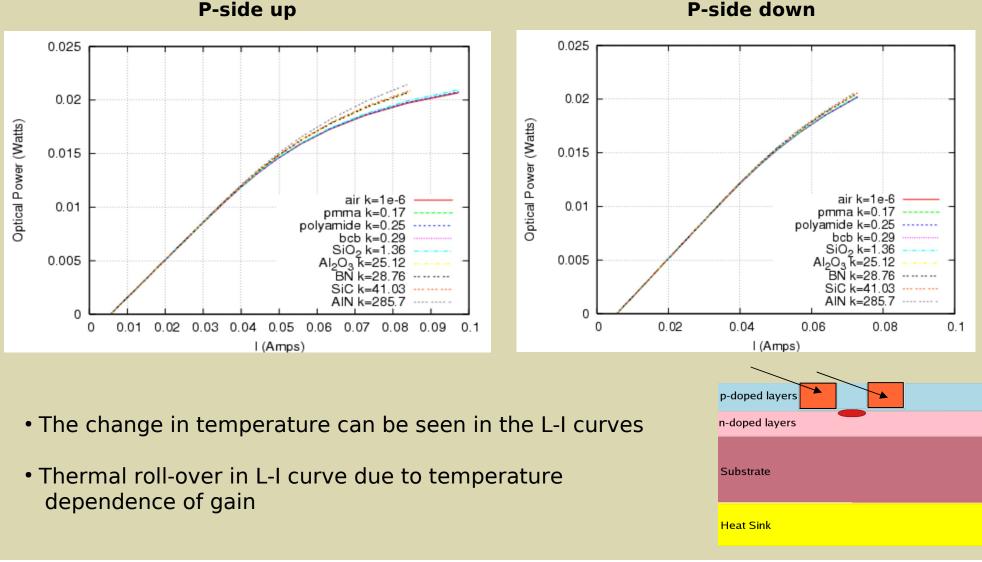


- Material system makes a large impact for p-side up mounted devices
- Less impact for p-side down mounting

Thermal conductivity of the etched trench



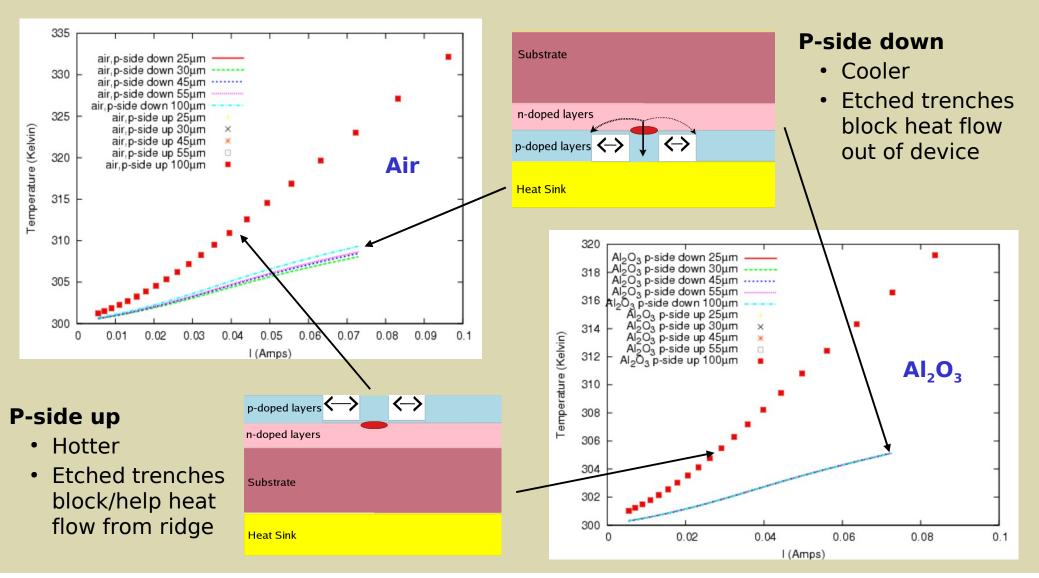
P-side down



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Variation of etch trench width

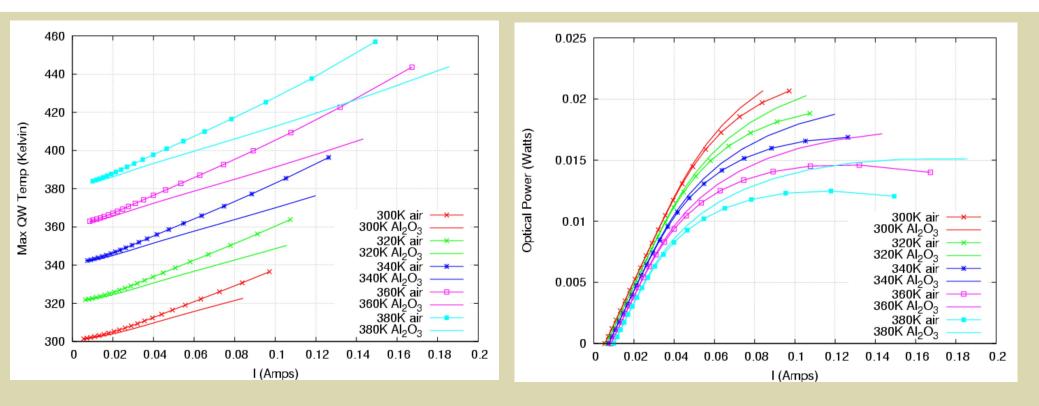




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Operation at elevated temperature





- Devices often operate in a poor thermal environment \rightarrow increased heat sink temperatures
- Filled etched trenches at high temperatures \rightarrow significant performance improvements
- Operating temperature strongly affects device reliability and life time

Conclusions



- The thermal mesh should extend 100 μ m laterally beyond the etched trenches and 100 μ m vertically into the heat sink
- There is a significant thermal penalty for p-side up mounting
- A thinner substrate results in a lower QW temperature
- Refilling the trenches with a thermally conductive material significantly reduces the QW temperature.
- A wider ridge reduces electrical resistance
 - Reduces Joule heating and decreases the thermal series resistance of the ridge
 - For a single-mode device, there is a limit to how wide the ridge can be
- The design of uncooled lasers requires the global optimisation of their thermal, electrical and optical performance (usually requiring a trade-off).

Thank you for your attention

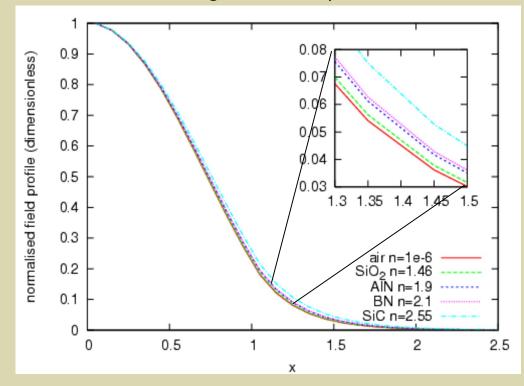


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What are the optical penalties of filling the trenches?



- More poorly confined lateral mode
 - Slightly worse confinement factor (minimal)
 - However this loss is more than compensated for by improved thermal performance



Ridge width = $2\mu m$

<u>Trend</u>: The larger the refractive index of the trench, the worse the guiding

With decrease in index step and width of etch leaky modes are more likely to cause problems

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